

3.3 V FCC/JATE DIRECT ACCESS ARRANGEMENT

Support for Caller ID

Low Profile SOIC Packages

Compliant with FCC Part 68

Proprietary ISOcap[™] Technology

Pin Compatible with Si3034, Si3032

Low-Power Standby Mode

Optional IIR Digital Filter

Fax Machines

Set Top Boxes

Direct Interface to DSPs

Integrated Modem Codec

Features

Complete DAA includes the following:

- 3.3 V to 5 V Digital/Analog **Power Supplies**
- JATE Filter Option
- 86 dB Dynamic Range TX/RX Paths
- Daisy-Chaining for Up to Eight Devices
- Integrated Ring Detector
- 3000 V Isolation

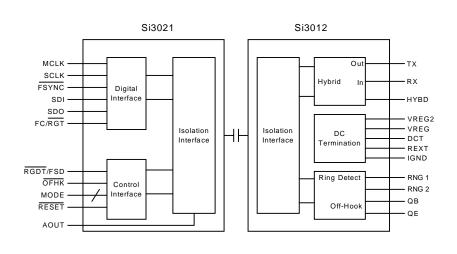
Applications

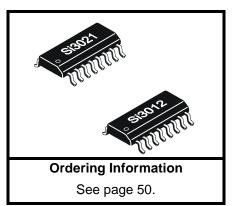
- V.90 Modems
- Voice Mail Systems

Description

The Si3035 is an integrated direct access arrangement (DAA) chipset that provides a digital, lo w-cost, solid-state in terface to a t elephone lin e. Available in two 16-pin small outline packages, it eliminates the need for an analog front end (AFE), an isolation transformer, relays, opto-isolators, and a 2-t o 4-wire hybrid. The Si3 035 dra matically red uces the num ber of discrete components and cost required to achieve compliance with FCC Part 6 8. The Si3 035 int erfaces d irectly to s tandard modem DSPs and supports all F CC and JATE out-of-band noise requirements. International support is provided by the pin compatible Si3034.

Functional Block Diagram





Pi	n Assign	ments					
Si3021 (SOIC)							
MCLK	1 ● 2 3 4 5 6 7 8	16 OFHK 15 RGDT/FSD 14 M0 13 V _A 12 GND 11 C1A 10 M1 9 AOUT					
S	6i3021 (TS	SOP)					
SDO SDI FC/RGDT RESET AOUT M1 C1A GND	1 ● 2 3 4 5 6 7 8	$\begin{array}{c c c c c c c c c c c c c c c c c c c $					
Si301	2 (SOIC o	r TSSOP)					
TSTA TSTB IGND C1B RNG1 RNG2 QB QE	1 ● 2 3 4 5 6 7 8	16 TX 15 NC 14 RX 13 REXT 12 DCT 11 HYBD 10 VREG2 9 VREG					

US Patent # 5,870,046 US Patent # 6,061,009 Other Patents Pending

Rev. 1.2 12/00



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Electrical Specifications

Table 1. Recommended Operating Conditions

Parameter ¹	Symbol	Test Condition	Min ²	Тур	Max ²	Unit
Ambient Temperature	Τ _Α	K-Grade	0	25	70	°C
Si3021 Supply Voltage, Analog	V _A		4.75	5.0	5.25	V
Si3021 Supply Voltage, Digital ³	VD		3.0	3.3/5.0	5.25	V

Notes:

1. The Si3035 specifications are guaranteed when the typical application circuit (including component tolerances) and any Si3021 and any Si3012 are used. See Figure 16 on page 15 for typical application circuit.

2. All minimum and maximum specifications are guaranteed and apply across the recommended operating conditions. Typical values apply at nominal supply voltages and an operating temperature of 25 °C unless otherwise stated.

 The digital supply, V_D, can operate from either 3.3 V or 5.0 V. The Si3021 supports interface to 3.3 V logic when operating from 3.3 V. The 3.3 V operation applies to both the serial port and the digital signals RGDT, OFHK, RESET, M0, and M1.

Table 2. Loop Characteristics

(V_A = Charge Pump, V_D = +3.3 V \pm 0.3 V, T_A = 0 to 70°C for K-Grade, Refer to Figure 1)

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
DC Termination Voltage	V _{TR}	I _L = 20 mA		_	7.7	V
DC Termination Voltage	V _{TR}	I _L = 105 mA	12	_		V
DC Ring Current (with caller ID)	I _{RDC}			_	— 1	mA
DC Ring Current (w/o caller ID)	I _{RDC}			_	<u> </u>	μA
AC Termination Impedance	Z _{ACT}			600	_	Ω
Operating Loop Current	I _{LP}		20	—	120	mA
Loop Current Sense Bits	LCS	LCS = Fh	180	155		mA
Ring Voltage Detect	V _{RD}		13	18	26	V _{RMS}
Ring Frequency	F _R		15	—	68	Hz
On-Hook Leakage Current	I _{LK}	$V_{BAT} = -48 V$		_	1	μA
Ringer Equivalence Num. (with caller ID)	REN			1.0	1.67	—
Ringer Equivalence Num. (w/o caller ID)	REN			0.2	—	

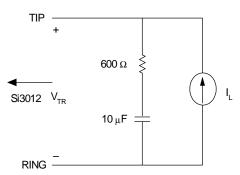






Table 3. DC Characteristics, V_D = +5 V

 $(V_A = +5 V \pm 5\%, V_D = +5 V \pm 5\%, T_A = 0 \text{ to } 70^{\circ}\text{C} \text{ for K-Grade})$

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
High Level Input Voltage	V _{IH}		3.5		—	V
Low Level Input Voltage	V _{IL}		—	_	0.8	V
High Level Output Voltage	V _{OH}	I _O = -2 mA	3.5		_	V
Low Level Output Voltage	V _{OL}	I _O = 2 mA	_		0.4	V
Input Leakage Current	١L		-10		10	μA
Power Supply Current, Analog	I _A	V _A pin		0.3	1	mA
Power Supply Current, Digital ¹	Ι _D	V _D pin		14	18	mA
Total Supply Current, Sleep Mode ¹	$I_A + I_D$	PDN = 1, PDL = 0	—	1.3	2.5	mA
Total Supply Current, Deep Sleep ^{1,2}	I _A + I _D	PDN = 1, PDL = 1	_	0.04	0.5	mA
Notos:	1	l.	1	1	1	1

Notes:

 All inputs at 0.4 or V_D – 0.4 (CMOS levels). All inputs held static except clock and all outputs unloaded (Static I_{OUT} = 0 mA).

2. RGDT is not functional in this state.

Table 4. DC Characteristics, V_D = +3.3 V

(V_A = Charge Pump, V_D = +3.3 V \pm 0.3 V, T_A = 0 to 70°C for K-Grade)

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
High Level Input Voltage	V _{IH}		2.0	_		V
Low Level Input Voltage	V _{IL}				0.8	V
High Level Output Voltage	V _{OH}	I _O = -2 mA	2.4		_	V
Low Level Output Voltage	V _{OL}	I _O = 2 mA		_	0.35	V
Input Leakage Current	١ _L		-10		10	μA
Power Supply Current, Analog ^{1,2}	I _A	V _A pin	—	0.3	1	mA
Power Supply Current, Digital ³	I _D	V _D pin	—	9	12	mA
Total Supply Current, Sleep Mode ³	I _A + I _D	PDN = 1, PDL = 0	—	1.2	2.5	mA
Total Supply Current, Deep Sleep ^{3,4}	I _A + I _D	PDN = 1, PDL = 1	_	0.04	0.5	
Power Supply Voltage, Analog ^{1,5}	V _A	Charge Pump On	4.3	4.6	5.00	V

Notes:

- 1. Only a decoupling capacitor should be connected to V_{A} when the charge pump is on.
- 2. There is no I_A current consumption when the internal charge pump is enabled and only a decoupling cap is connected to the V_A pin.
- All inputs at 0.4 or V_D 0.4 (CMOS levels). All inputs held static except clock and all outputs unloaded (Static I_{OUT} = 0 mA).
- **4.** RGDT is not functional in this state.
- 5. The charge pump is recommended to be used only when $V_D < 4.5$ V. When the charge pump is not used, V_A should be applied to the device before V_D is applied on power up if driven from separate supplies.



Table 5. AC Characteristics

(V_A = Charge Pump, V_D = +3.3 V \pm 0.3 V, T_A = 0 to 70°C for K-Grade)

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Sample Rate ¹	Fs	Fs = F _{PLL2} /5120	7.2	—	11.025	kHz
PLL1 Output Clock Frequency	F _{PLL1}	FPLL1 = F _{MCLK} • M1/N1	36	—	58	MHz
Transmit Frequency Response		Low –3 dB corner	_	16	_	Hz
Receive Frequency Response		Low –3 dB corner		16		Hz
Transmit Full Scale Level ² (0 dB gain)	V _{TX}		—0	.98		V_{PEAK}
Receive Full Scale Level ^{2,3} (0 dB gain)	V _{RX}		—0	.98		V _{PEAK}
Dynamic Range ⁴	DR	VIN = 1 kHz, –3 dBFS	80	86	_	dB
Dynamic Range ⁵	DR	VIN = 1 kHz, –3 dBFS	_	84	_	dB
Total Harmonic Distortion ⁶	THD	VIN = 1 kHz, –3 dBFS		-84		dB
Dynamic Range (call progress AOUT)	DR _{AO}	VIN = 1 kHz	60			dB
THD (call progress AOUT)	THD _{AO}	VIN = 1 kHz	_	1.0	_	%
AOUT Full Scale Level				0.75 V _D	—V	PP
AOUT Output Impedance				10		kΩ
Mute Level (call progress AOUT)			-90	—	_	dB
Dynamic Range (caller ID mode)	DR _{CID}	VIN = 1 kHz, –13 dBFS		60		dB
Caller ID Full Scale Level (0 dB gain) ²	V _{CID}		—0	.8		V_{PEAK}

Notes:

1. See Figure 23 on page 22.

2. Parameter measured at TIP and RING of Figure 16 on page 15.

3. Receive Full Scale Level will produce - 0.9 dBFS at SDO.

4. DR = 3 dB + 20 log (RMS signal/RMS noise). Applies to both the transmit and receive paths. Measurement bandwidth is 300 to 3400 Hz. Sample Rate = 9.6 kHz, Loop Current = 40 mA.

5. DR = 3 dB + 20 log (RMS signal/RMS noise). Applies to both the transmit and receive paths. Measurement bandwidth is 15 to 3400 Hz. Sample Rate = 9.6 kHz, Loop Current = 40 mA.

 THD = 20 log (RMS distortion/RMS signal). Applies to both the transmit and receive paths. Sample Rate = 9.6 kHz, Loop Current = 40 mA.



Table 6. Absolute Maximum Ratings

Symbol	Value	Unit
V _D , V _A	-0.5 to 6.0	V
I _{IN}	±10	mA
V _{IND}	–0.3 to (V _D + 0.3)	V
T _A	-40 to 100	°C
T _{STG}	-65 to 150	°C
	V _D , V _A I _{IN} V _{IND} T _A	V_D, V_A -0.5 to 6.0 I_{IN} ±10 V_{IND} -0.3 to $(V_D + 0.3)$ T_A -40 to 100

Note: Permanent device damage may occur if the above Absolute Maximum Ratings are exceeded. Functional operation should be restricted to the conditions as specified in the operational sections of this data sheet. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Table 7. Switching Characteristics—General Inputs

(V_A = Charge Pump, V_D = 3.0 to 5.25 V, T_A = 0 to 70°C for K-Grade, C_L = 20 pF)

Parameter ¹	Symbol	Min	Тур	Мах	Unit
Cycle Time, MCLK	t _{mc}	16.67	_	1000	ns
MCLK Duty Cycle	t _{dty}	40	50	60	%
Rise Time, MCLK	t _r			5	ns
Fall Time, MCLK	t _f	—	—	5	ns
MCLK Before RESET ↑	t _{mr}	10	—	_	cycles
RESET Pulse Width ²	t _{rl}	250	—	—	ns
M0, M1 Before RESET ^{↑3}	t _{mxr}	150	—	—	ns

Notes:

1. All timing (except Rise and Fall time) is referenced to the 50% level of the waveform. Input test levels are

- $V_{IH} = V_D 0.4 \text{ V}, V_{IL} = 0.4 \text{ V}$. Rise and Fall times are referenced to the 20% and 80% levels of the waveform. 2. The minimum RESET pulse width is the greater of 250 ns or 10 MCLK cycle times. 3. M0 and M1 are typically connected to V_D or GND and should not be changed during normal operation.

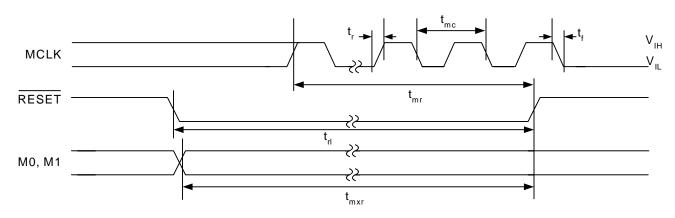






Table 8. Switching Characteristics—Serial Interface (DCE = 0)

 $(V_A = Charge Pump, V_D = 3.0 \text{ to } 5.25 \text{ V}, T_A = 0 \text{ to } 70^{\circ}C \text{ for K-Grade}, C_L = 20 \text{ pF})$

Parameter	Symbol	Min	Тур	Max	Unit
Cycle time, SCLK	t _c	354	1/256 Fs	_	ns
SCLK duty cycle	t _{dty}	—5	0		%
Delay time, SCLK \uparrow to $\overline{FSYNC} \downarrow$	t _{d1}		_	10	ns
Delay time, SCLK \uparrow to SDO valid	t _{d2}	_	—	20	ns
Delay time, SCLK \uparrow to FSYNC \uparrow	t _{d3}	_	_	10	ns
Setup time, SDI before SCLK \downarrow	t _{su}	25	_	_	ns
Hold time, SDI after SCLK \downarrow	t _h	20	_		ns
Setup time, FC \uparrow before SCLK \uparrow	t _{sfc}	40	_	_	ns
Hold time, FC \uparrow after SCLK \uparrow	t _{hfc}	40	_	_	ns

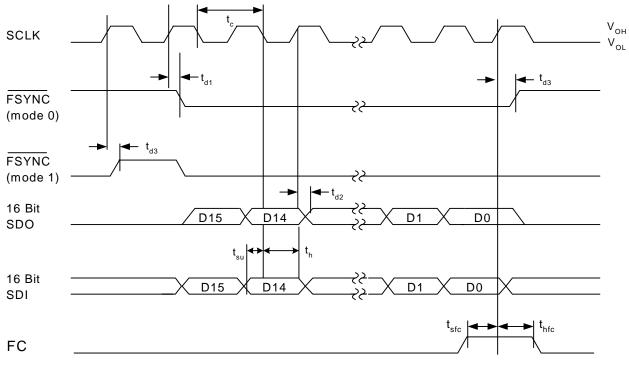


Figure 3. Serial Interface Timing Diagram



Table 9. Switching Characteristics—Serial Interface (DCE = 1, FSD = 0)

Parameter ^{1,2}	Symbol	Min	Тур	Мах	Unit
Cycle Time, SCLK	t _c	354	1/256 Fs		ns
SCLK Duty Cycle	t _{dty}	—5	0	—	%
Delay Time, SCLK \uparrow to FSYNC \uparrow	t _{d1}	_	—	10	ns
Delay Time, SCLK \uparrow to $\overline{FSYNC} \downarrow$	t _{d2}	_	—	10	ns
Delay Time, SCLK \uparrow to SDO valid	t _{d3}	0.25t _c – 20	—	0.25t _c + 20	ns
Delay Time, SCLK \uparrow to SDO Hi-Z	t _{d4}	_	—	20	ns
Delay Time, SCLK \uparrow to $\overline{RGDT}\downarrow$	t _{d5}	_	—	20	ns
Delay Time, SCLK \uparrow to \overline{RGDT} \uparrow	t _{d6}	_	—	20	ns
Setup Time, SDO Before SCLK \downarrow	t _{su}	25			ns
Hold Time, SDO After SCLK \downarrow	t _h	20	—		ns
Setup Time, SDI Before SCLK	t _{su2}	25	—		ns
Hold Time, SDI After SCLK	t _{h2}	20	—		ns
Notes:		4	1	1	1

(V_A = Charge Pump, V_D = 3.0 to 5.25 V, T_A = 0 to 70°C for K-Grade, C_L = 20 pF)

1. All timing is referenced to the 50% level of the waveform. Input test levels are $V_{IH} = V_D - 0.4$ V, $V_{IL} = 0.4$ V.

2. Refer to the section "Multiple Device Support" on page 25 for functional details.

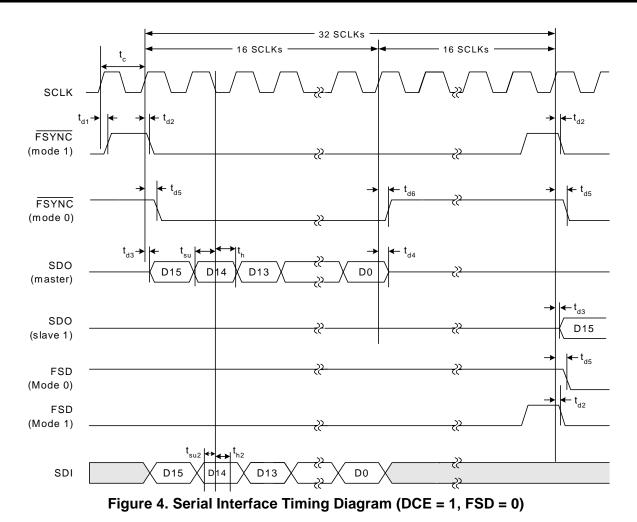




Table 10. Switching Characteristics—Serial Interface (DCE = 1, FSD = 1)

(V_A = Charge Pump, V_D = 3.0 to 5.25 V, T_A = 0 to 70°C for K-Grade, C_L = 20 pF)

Parameter ^{1,2}	Symbol	Min	Тур	Мах	Unit
Cycle Time, SCLK	t _c	354	1/256 Fs		ns
SCLK Duty Cycle	t _{dty}	—5	0		%
Delay Time, SCLK \uparrow to FSYNC \uparrow	t _{d1}	_	_	10	ns
Delay Time, SCLK \uparrow to \overline{FSYNC} \downarrow	t _{d2}	_	_	10	ns
Delay Time, SCLK \uparrow to SDO valid	t _{d3}	0.25t _c – 20	—	0.25t _c + 20	ns
Delay Time, SCLK [↑] to SDO Hi-Z	t _{d4}	_	_	20	ns
Delay Time, SCLK \uparrow to $\overline{RGDT}\downarrow$	t _{d5}	_	—	20	ns
Setup Time, SDO Before SCLK \downarrow	t _{su}	25	—		ns
Hold Time, SDO After SCLK \downarrow	t _h	20	_		ns
Setup Time, SDI Before SCLK	t _{su2}	25	_	_	ns
Hold Time, SDI After SCLK	t _{h2}	20	_		ns
			l	+	1

Notes:

1. All timing is referenced to the 50% level of the waveform. Input test levels are $V_{IH} = V_D - 0.4$ V, $V_{IL} = 0.4$ V.

2. Refer to the section "Multiple Device Support" on page 25 for functional details.

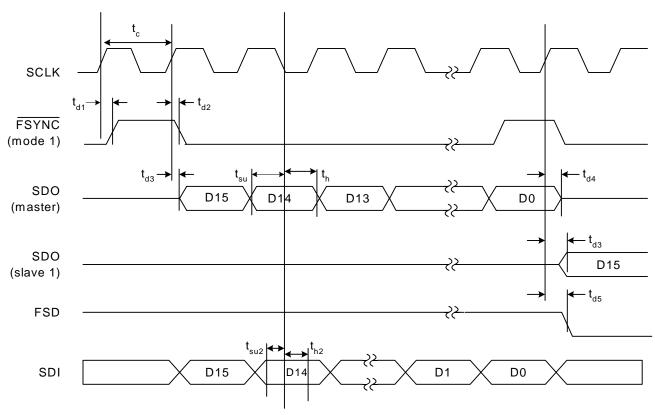






Table 11. Digital FIR Filter Characteristics—Transmit and Receive

 $(V_A = Charge Pump, V_D = +5 V \pm 5\%$, Sample Rate = 8 kHz, $T_A = 0$ to 70°C for K-Grade)

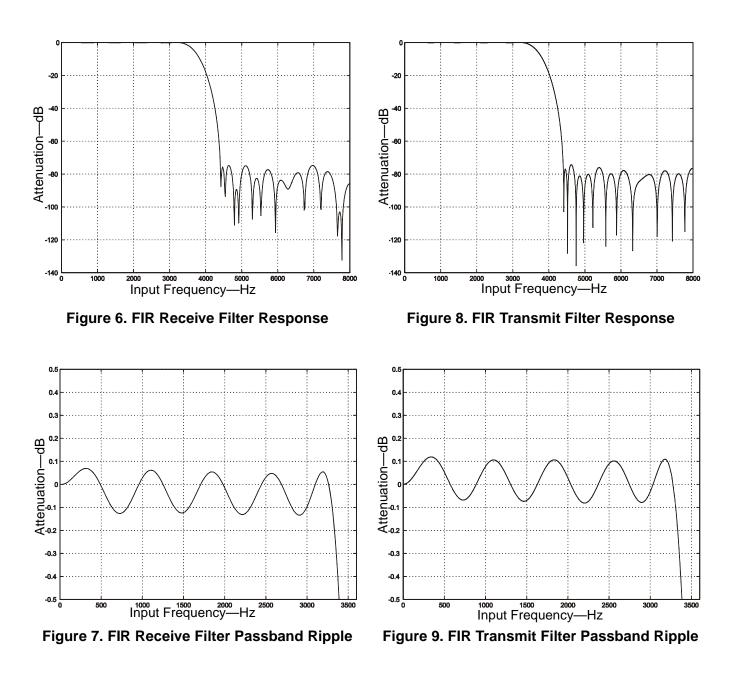
Parameter	Symbol	Min	Тур	Max	Unit							
Passband (0.1 dB)	F _(0.1 dB)	0—		3.3	kHz							
Passband (3 dB)	F _(3 dB)	0—		3.6	kHz							
Passband Ripple Peak-to-Peak		-0.1	_	0.1	dB							
Stopband		_	4.4		kHz							
Stopband Attenuation		-74	—		dB							
Group Delay	t _{gd}	_	12/Fs		sec							
Note: Typical FIR filter characteristics for	Fs = 8000 Hz are s	shown in Figures	6, 7, 8, and 9.	Note: Typical FIR filter characteristics for Fs = 8000 Hz are shown in Figures 6, 7, 8, and 9.								

Table 12. Digital IIR Filter Characteristics—Transmit and Receive

 $(V_A = Charge Pump, V_D = +5 V \pm 5\%$, Sample Rate = 8 kHz, $T_A = 0$ to 70°C for K-Grade)

Parameter	Symbol	Min	Тур	Max	Unit
Passband (3 dB)	F _(3 dB)	0—		3.6	kHz
Passband Ripple Peak-to-Peak		-0.2	_	0.2	dB
Stopband		_	4.4		kHz
Stopband Attenuation		-40			dB
Group Delay	t _{gd}		1.6/Fs		sec
Note: Typical IIR filter characteristics for F group delay versus input frequency.	s = 800 0 Hz are s	shown in Figure	s 10, 11, 12, an	d 13. Figures 1	4 and 15 show





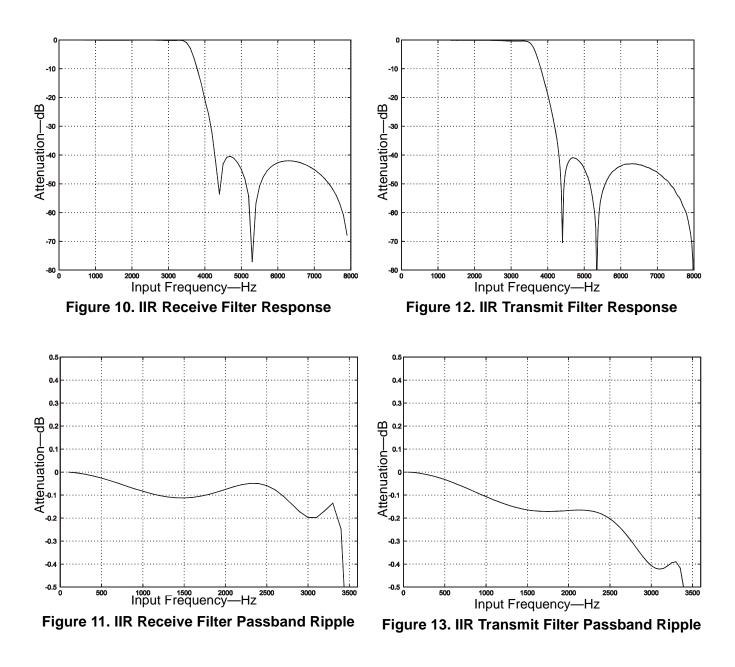
For Figures 6–9, all filter plots apply to a sample rate of Fs = 8 kHz. The filters scale with the sample rate as follows:

$$F_{(0.1 \text{ dB})} = 0.4125 \text{ Fs}$$

$$F_{(-3 dB)} = 0.45 Fs$$

where Fs is the sample frequency.



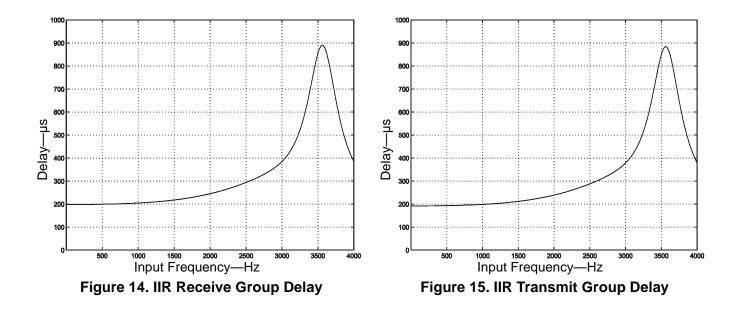


For Figures 10–13, all filter plots apply to a sample rate of Fs = 8 kHz. The filters scale with the sample rate as follows:

 $F_{(-3 \text{ dB})} = 0.45 \text{ Fs}$

where Fs is the sample frequency.

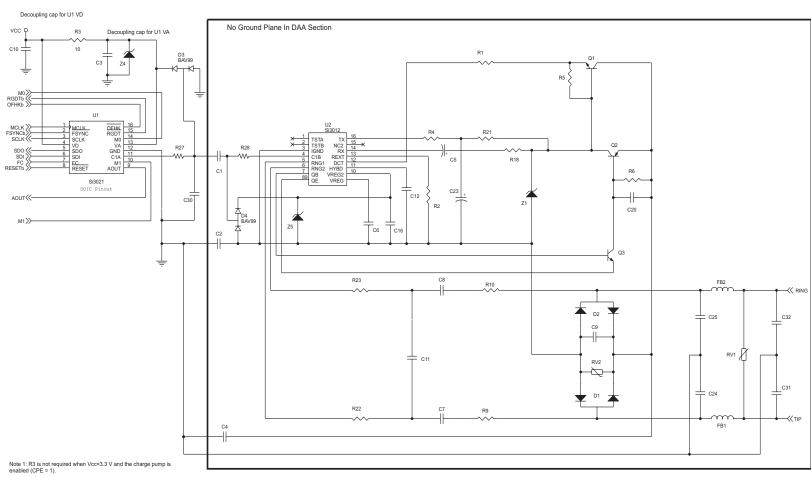






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Rev. 1.2



Note 2: If JATE support is not required, R21, C12 and C23 may be removed (R21 is effectively 0 ohms) and R4 should be changed to a 604 ohm, 1/4 W, +- 1%.

Note 3: See Appendix for applications requiring UL 1950 3rd Edition compliance.

Figure 16. Typical Application Schematic

Typical Application Circuit

Bill of Materials

Component ¹	Value	Supplier(s)
C1,C4	150 pF, 3 kV, X7R, ±20%	Novacap, Venkel, Johanson, Murata, Panasonic, SMEC
C2	Not Installed	
C3	0.22 μF, 16 V, X7R, ±20%	
C5	1 μF, 16 V, Tant/Elec, ±20%	
C6,C10,C16	0.1 μF, 16 V, X7R, ±20%	
C7,C8,C9	15 nF, 250 V, X7R, ±20%	Novacap, Johanson, Murata, Panasonic, SMEC
C11	39 nF, 16 V, X7R, ±20%	
C12 ²	2.7 nF, 16 V, X7R, ±20%	
C23 ²	0.1 μF, 16 V, Tant/Elec/X7R, ±20%	
C24, C25, C31,C32 ³ 1000 pF, 3 kV, X7R, ±10%		Novacap, Venkel, Johanson, Murata, Panasonic, SMEC
C30 ⁴	Not Installed	
D1,D2 ⁵	Dual Diode, 300 V, 225 mA	Central Semiconductor
D3,D4	BAV99 Dual Diode, 70 V, 350 mW	Diodes, Inc., OnSemiconductor, Fairchild
FB1,FB2	Ferrite Bead	Murata
Q1,Q3	A42, NPN, 300 V	OnSemiconductor, Fairchild
Q2	A92, NPN, 300 V	OnSemiconductor, Fairchild
RV1	Sidactor, 275 V, 100 A	Teccor, ST Microelectronics, Microsemi, TI
RV2	MOV, 240 V	Panasonic
R1	51 Ω, 1/2 W ±5%	
R2	15 Ω, 1/4 W ±5%	
R3 ⁶	Not Installed	
R4 ² ,R18,R21 ²	301 Ω, 1/10 W, ±1%	
R5,R6	36 kΩ, 1/10 W ±5%	
R9,R10	2 kΩ, 1/10 W ±5%	
R22,R23	20 kΩ, 1/10 W ±5%	
R27,R28	10 Ω, 1/10 W ±5%	
U1	Si3021	Silicon Labs
U2	Si3012	Silicon Labs
Z1	Zener diode, 18 V	Vishay, Rohm, OnSemiconductor
Z4,Z5	Zener diode, 5.6 V, 1/2 W	Diodes, Inc., OnSemiconductor, Fairchild

Table 13. Component Values—Typical Application

Notes:

1. The following reference designators were intentionally omitted: C13–C15, C17–C22, C26–C29, R7, R8, R11–R17, R19, and R20.

- 2. If JATE support is not required, C12, and C23 may be removed.
- 3. Alternate population option is C24, C25 (2200 pF, 3 kV, X7R, ±10% and C31, C32 not installed).
- 4. Install only if needed for improved radiated emissions performance (10 pF, 16 V, NPO, ±10%).
- 5. Several diode bridge configurations are acceptable (suppliers include General Semi, Diodes Inc.)

6. If the charge pump is not enabled (with the CPE bit in Register 6), V_A must be 4.75 to 5.25 V. R3 can be installed with a 10 Ω , 1/10 W, ±5% if V_D is also 4.75 to 5.25 V.



Analog Output

Figure 17 illustrates an opt ional application circuit to support the an alog output capability of the Si3035 for call progress monitoring purposes. The ARM bits in Register 6 allow the receive path to be attenuated by 0 dB, -6 dB, or -12 dB. The ATM bits, which are also in Register 6, allow the transmit path to be attenuated by -20 dB, -26 dB, or -32 dB. Both the transmit and receive paths can also be independently muted.

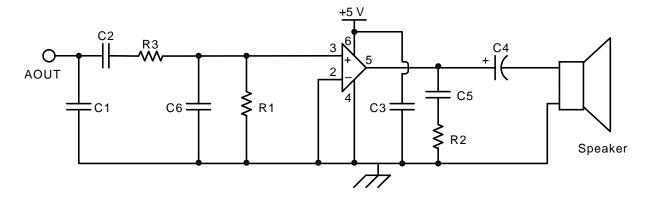


Figure 17. Optional Connection to AOUT for a Call Progress Speaker

Symbol	Value
C1	2200 pF, 16 V, ±20%
C2, C3, C5	0.1 μF, 16 V, ±20%
C4	100 µF, 16 V, Elec. ±20%
C6	820 pF, 16 V, ±20%
R1	3 kΩ, 1/10 W, ±5%
R2	10 Ω, 1/10 W, ±5%
R3	47 kΩ, 1/10 W, ±5%
U1	LM386

Table 14. Component Values—Optional Connection to AOUT



Functional Description

The Si 3035 is an in tegrated c hipset that pr ovides a low-cost, i solated, si licon-based in terface t o th e telephone line. The Si 3035 saves cost and board area by eliminating the need for a mo dem AFE or s erial codec. It a lso el iminates the need for an i solation transformer, rel ays, o pto-isolators, a nd a 2- to 4-wi re hybrid. T he S i3035 solution r equires o nly a fe w low-cost, di screte components to ac hieve full compliance wi th FCC P art 68 an d J ATE ou t-of-band noise requirements. See F igure 16 on pag e 15 for a typical app lication ci rcuit. S ee the p in-compatible Si3034 or Si3044 da ta sh eets for designs r equiring global support.

The Si3035 North America/Japan DAA offers a number of new feat ures not s upported by the Si 3032 device. These in clude operation fr om a s ingle 3.3 V power supply, J ATE (Japan) fil ter option, fin er resolution for both transmit and receive levels on AOUT (call progress output), da isy-chaining for up to eight devices, and an optional IIR filter. Table 15 summarizes the new Si3035 features.

Category	Si3032	Si3035			
Daisy-Chaining	_	Up to 8 Devices			
Optional IIR Filter	_	Yes			
Receive Gain	0, 6 dB	0, 3, 6, 9, 12 dB			
Transmit Attenuation	0, –3 dB	0, -3, -6 -9, -12 dB			
V _A	5 V	3.3 V* or 5 V			
V _D	3.3 V or 5 V	3.3 V or 5 V			
JATE Support	_	Yes			
AOUT Levels (dB)	0, mute	0, -6, -12, mute			
*Note: The V _A supply is internally generated by an on-c hip charge pump.					

Table 15. New Si3035 Features

Initialization

When the Si3035 is initially powered up, the RESET pin should be as serted. When the RESET pin is deasserted, the registers will have default values. This reset condition guarantees the line-side chip (Si3012) is powered down with no possibility of loading the line (i.e., off-hook). The following is an example initialization

procedure:

- Program the PLLs with registers 7 to 9 (N1[7:0], M1[7:0], N2[3:0] and M2[3:0]) to the appropriate divider ratios for the supplied MCLK frequency and desired sample rate, as defined in "Clock Generation Subsystem" on page 20.
- 2. Wait until the PLLs are locked. This time is between 100 μS and 1 ms.
- 3. Write an 0x80 into Register 6. This enables the charge pump for the V_A pin, powers up the line-side chip (Si3012), and enables the AOUT for call progress monitoring.

After this procedure is complete, the Si3035 is ready for ring detection and off-hook.

Isolation Barrier

The S i3035 achieves an isolation bar rier th rough a low-cost, high-voltage ca pacitor in co njunction w ith Silicon La boratories' pr oprietary IS Ocap signal processing techniques. These techniques eliminate any signal d egradation due to ca pacitor mis matches, common m ode in terference, or no ise c oupling. As shown in Figure 16 on p age 15, th e C1, C2, and C4 capacitors i solate the S i3021 (DSP-side) fr om th e Si3012 (line-side). All tr ansmit, r eceive, c ontrol, and caller ID data are communicated through this barrier.

The ISOcap i nter-chip c ommunication is d isabled by default. To enable it, the PDL bit in Register 6 must be cleared. No c ommunication b etween the Si 3021 and Si3012 c an oc cur until this b it is c leared. The c lock generator *must* be pr ogrammed to an ac ceptable sample rate prior to clearing the PDL bit.

Off-Hook

The c ommunication system g enerates an off-hook command by applying logic 0 to the OFHK pin or writing a logic 1 to bit 0 of control Register 5. The OFHK pin must be enabled by setting bit 1 (OHE) of Register 5. With OFHK at logic 0, the system is in an off-hook state. This state is used to seize the line for incoming/outgoing calls and can also be used for pulse dialing. With OFHK at log ic 1, neg ligible DC current flo ws thr ough the hookswitch. When a logic 0 is applied to the OFHK pin, the hookswitch transistor pair, Q1 and Q2, turn on. The net effect of the off-hook signal is the application of a termination im pedance ac ross T IP and RING and the flow of DC loop current. The termination impedance has both an AC and a DC component.

The A C termination i mpedance is a 60 4- Ω resistor, which is connected to the TX pin. The DC termination is a 51- Ω resistor, which is connected to the DCT pin.

When e xecuting an off-hook sequence, the Si 3035 requires 1548/Fs seconds to complete the off-hook and provide phone line data on the serial link. This includes the 12/Fs filter group delay. If necessary, for the shortest



delay, a higher Fs may be established prior to executing the off-hook, such as an F s of 10.2 86 kHz. The delay allows line transients to settle prior to normal use.

Ring Detect

The r ing si gnal en ters the Si 3035 thr ough I ow value capacitors connected t o T IP and RING. RGDT is a clipped, h alf-wave r ectified v ersion of the ringing waveform. See Figure 18 for a timing diagram of the RGDT pin.

The i ntegrated r ing d etect o f the S i3035 al lows th e device to present the ring signal to the DSP, through the serial port, with no add itional signaling r equired. The signal sent to the DSP is a clipped version of the original ring signal. In ad dition, the S i3035 p asses through the caller ID data unaltered.

The system can al so detect an oc curring ring by the status of the RDT bit of Regi ster 5. T his bit is a read-only b it that is s et when the line-side de vice detects a ring signal at RNG 1 and RNG2. The RDT bit clears when the system either goes off-hook or 4.5 to 9 seconds after the last ring is detected.

If caller ID is supported in the system, the designer can enable the S i3035 to pass this information to the SDO output. Following t he completion of the first r ing, the system should set the ONHM bit (Register 5, bit 3). This bit must be c leared at the conclusion of the receipt of the caller ID data and prior to the next ring burst.

The S i30<u>21 can</u> s upport a w ake-up-on-ring function using the RGDT signal. Refer to "Power Management" on page 24 for more details

Improved JATE Support

The HYBD pin connects to a node on the internal hybrid cancellation c ircuit pr oviding a p in for a b alancing capacitor, C12. C23 ad ds the ne cessary transmit out-of-band filtering required to meet JATE out-of-band noise sp ecifications. T he ad dition of C23 alt ers th e transmit pa th fr equency r esponse whi ch mus t b e balanced with capacitor C12 to obtain maximum hybrid cancellation.

Products using the Si3035 which have been submitted for J ATE ap proval should document a wai ver for the JATE DC Termination specification. This specification is met in the Si3034 global DAA device.

Digital Interface

The Si3035 has two serial interface modes that support most standard modem DS Ps. The M0 and M1 mode pins s elect the interface mode. The key difference between these two serial modes is the operation of the FSYNC s ignal. Table 16 s ummarizes the serial mode definitions.

Table 16. Serial Modes

Mode	M1 M0		Description
0	0	0	FSYNC frames data
1	0	1	FSYNC pulse starts data frame
2	1	0	Slave mode
3	1	1	Reserved

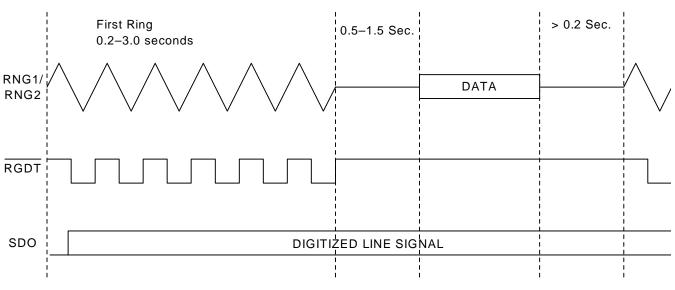


Figure 18. Ring Detect Timing



Si3035

The digital interface consists of a single, synchronous serial link which communicates both telephony and control data.

In Serial mode 0 or 1, the Si3021 operates as a master, where the master clock (MCLK) is an input, the serial data cl <u>ock (SCLK)</u> is an output, and the fr ame sy nc signal (FSYNC) is an output. The MCLK frequency and the value of the s ample rate control registers 7, 8, 9, and 10 determine the sample rate (Fs). The serial port clock, SCLK, r uns at 256 bits per fr ame, where the frame r ate is equivalent to the sample rate. Re fer to "Clock Generation S ubsystem" on pag e 20 fo r mo re details on programming sample rates.

The Si3035 transfers 16-bit or 15-bit telephony data in the pr imary ti meslot and 1 6-bit c ontrol d ata in the secondary tim eslot. Figure 19 and Figure 20 s how the relative tim ing of the s erial fr ames. Pr imary frames occur at the f rame r ate a nd a re al ways present. To minimize ov erhead i n the ex ternal DS P, se condary frames are present only when requested.

Two methods exist for transferring control information in the secondary frame. The default power-up mode uses the LSB of the 16-bit transmit (TX) data word as a flag to req uest a s econdary tran sfer. In thi s m ode, on ly 15-bit TX data is transferred, resulting in a loss of SNR but allowing software control of the secondary frames. As an alternative method, the FC pin can serve as a hardware flag for requesting a se condary frame. The external DSP can turn on the 16-bit TX mode by setting the SB bit of R egister 1. In the 16-bit TX mode, th e hardware FC pin must be us ed to request se condary transfers.

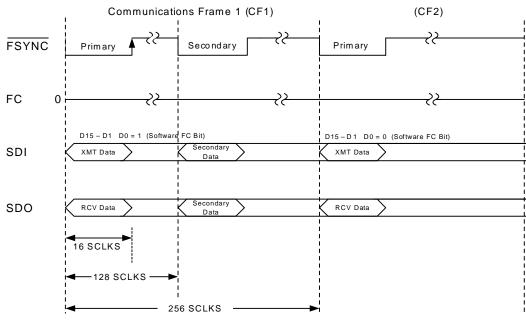
Figure 21 and Figure 22 illustrate the secondary frame read cycle and write cycle, respectively. During a read cycle, the R/W b it is high and the 5-bit address field contains the ad dress of the register to be r ead. The contents of the 8-bit control register are placed on the SDO signal. During a write cycle, the R/W bit is low and the 5-bit a ddress field contains the address of the register to be wr itten. The 8- bit data to be wr itten immediately fo llows th e ad dress on S DI. Only on e register can be read or written during each se condary frame. Se e " Control Re gisters" on pa ge 3 4 for th e register addresses and functions.

In serial mode 2, the Si3021 operates as a slave device, where the MCLK is an input, the SCLK is a no connect (except for the master device for which it is an output), and the FSYNC is an input. In addition, the RGDT/FSD pin operates as a delayed frame sync (FSD) and the FC/RGDT pin operates as ring detect (RGDT). In this mode, FC operation is not supported. For further details on operating the S i3021 as a s lave de vice, r efer t o "Multiple Device Support" on page 25.

Clock Generation Subsystem

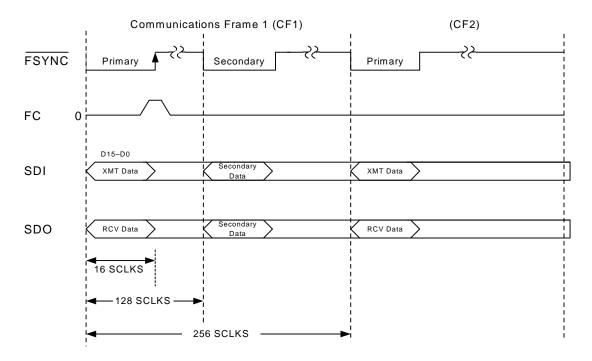
The Si3035 contains an on-chip clock generator. Using a si ngle MCL K in put fr equency, the Si 3035 ca n generate all the desired standard modem sample rates, as w ell a s the c ommon 1 1.025 k Hz r ate f or a udio playback.

The clock gen erator con sists of two PLLs (PLL1 and PLL2) t hat achieve the de sired s ample fr equencies. Figure 23 on page 22 illustrates the clock generator.











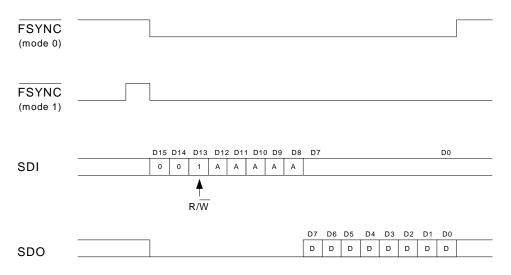


Figure 21. Secondary Communication Data Format—Read Cycle



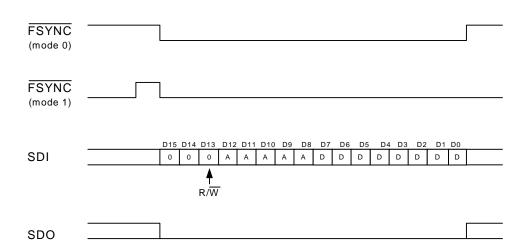


Figure 22. Secondary Communication Data Format—Write Cycle

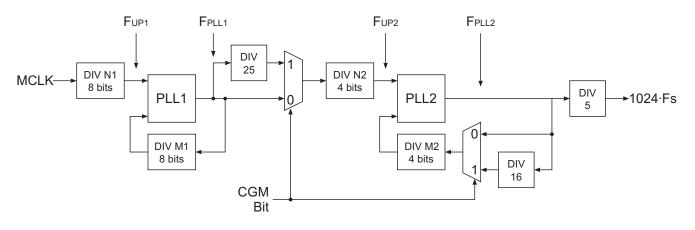


Figure 23. Clock Generation Subsystem

The architecture of the dual PLL scheme allows for fast lock time on in itial s tart-up, fas t lock ti me when changing modem sa mple r ates, hi gh no ise im munity, and the a bility to change modem sample r ates with a single register w rite. A I arge n umber o f M CLK frequencies between 1 MHz and 60 MHz are supported. MCLK sh ould be fr om a clean s ource, pr eferably directly from a crystal with a constant frequency and no dropped pulses.

In serial mode 2, the Si3021 operates as a slave device. The clock generator is configured (by default) to set the SCLK output equal to the MCLK input. The net effect is the clock generator multiplies the MCLK input by 20. For further details of slave mode operation, refer to "Multiple Device Support" on page 25.

Programming the Clock Generator

As noted in Figure 23, the clock generator must output a clock eq ual to 10 24 • Fs, whe re Fs is the des ired sample rate. The 1024 • Fs clock is determined through programming of the following registers:

Register 7-N1 divider, 8 bits.

Register 8-M1 divider, 8 bits.

Register 9-N2/M2 dividers, 4 bits/4 bits.

Register 10-CGM, 1 bit.

When using the S i3035 for mo dem ap plications, the clock generator can be programmed to allow for a single register wr ite to c hange the mo dem sa mpling r ate. These standard s ample rates ar e sh own in Table 17. The programming method is described below.



Fs (Hz)	N2	M2
7200	2	2
8000	9	10
8229	7	8
8400	6	7
9000	4	5
9600	3	4
10286	7	10

Table 17. N2, M2 Values (CGM = 0, 1)

The main de sign consideration is the generation of a base frequency, defined as the following:

$$F_{\text{Base}} = = \frac{F_{\text{MCLK}} \cdot M1}{N1} \quad 36.864 \text{MHz}, \text{@CGM} =$$

$$F_{\text{Base}} = = \frac{F_{\text{MCLK}} \cdot M1 \cdot 16}{N1 \cdot 25} \quad 6.864 \text{MHz}, \text{CGM} =$$

N1 (Register 7) and M1 (Register 8) are 8-bit unsigned values. F_{MCLK} is the clock provided to the MCLK pin. Table 18 lists s everal s tandard c rystal o scillator rates that could be s upplied to MCLK. T his list s imply represents a sample of MCLK frequency choices. Many more are possible.

After the first PLL has been setup, the second PLL can be programmed ea sily. The v alues for N2 and M 2 (Register 9) are shown in Table 17. N2 and M2 are 4-bit unsigned values.

When programming the registers of the clock generator, the order of r egister writes is i mportant. F or PLL1 updates, N1 (Register 7) must al ways be written first, immediately followed by a write to M1 (Register 8). For PLL2, the CG M bit must be set as de sired prior to writing N2/M2 (Register 9). Changes t o th e CG M bi t only take effect when N2/M2 are written.

Note: The values shown in Table 17 and Table 18 satisfy the equations above. H owever, w hen pr ogramming t he registers for N1, M1, N2, and M2, the value placed in these registers must be one less than the value calculated from the equations. For example, for CGM = 0with a MCLK of 48.0 MHz, the values placed in the N1 and M1 registers would be 0x 7C and 0x5F, respectively. If CGM = 1, a no n-zero value m ust be p rogrammed to Register 9 in orde r for the 16/25 ratio to take effect.

Table 18. MCLK Examples						
CLK (MHz)	N1	M1	CGN			
1.8432	1	20	0			
4.0000	5	72	1			
4.0960	1	9	0			
5.0688	11	80	0			
6 0000	5	48	1			

1.8432	1	20	0
4.0000	5	72	1
4.0960	1	9	0
5.0688	11	80	0
6.0000	5	48	1
6.1440	1	6	0
8.1920	32	225	1
9.2160	1	4	0
10.0000	25	144	1
10.3680	9	32	0
11.0592	3	10	0
12.288	1	3	0
14.7456	2	5	0
16.0000	5	18	1
18.4320	1	2	0
24.5760	32	75	1
25.8048	7	10	0
33.8688	147	160	0
44.2368	96	125	1
46.0800	5	4	0
47.9232	13	10	0
48.0000	125	96	0
56.0000	35	36	1
60.0000	25	24	1

PLL Lock Times

MC

The S i3035 c hanges s ample r ates v ery guickly. However, lock time will vary based on the programming of the clock generator. The major factor contributing to PLL lock time is the CGM bit. When the CGM bit is used (set to 1), PLL2 will lock slower than when CGM is 0. The following relationships describe the boundaries on PLL locking time:

PLL1 lock time < 1 ms (CGM = 0,1)

PLL2 lock time: 100 us to 1 ms (CGM = 0)

PLL2 lock time <1 ms (CGM = 1)

For modem designs, it is recommended that PLL1 be programmed dur ing in itialization. No further programming of PLL1 is necessary. The CGM bit and PLL2 can be programmed for the desired initial sample



rate, typically 7200 Hz. All further sample rate changes are then made by simply writing to Register 9 to update PLL2.

The final design consideration for the clock generator is the update rate of PLL1. The following criteria must be satisfied in order for the PLLs to remain stable:

$$F_{UP1} = \frac{F_{MCLK}}{N1} \ge 44 \text{ kHz}$$

Where F_{UP1} is shown in Figure 23 on page 22.

Setting Generic Sample Rates

The above clock generation description focuses on the common mo dem sa mple r ates. An a pplication may require a sample rate not listed in Table 17, such as the common audio rate of 11.025 kHz. The restrictions and equations a bove s till ap ply; h owever, a more generic relationship between MCLK and Fs (the desired sample rate) is n eeded. The following equation de scribes th is relationship:

$$\frac{M1 \cdot M2}{N1 \cdot N2} = ratio \cdot \frac{51 \cdot 024F s}{MCLK}$$

where F s is th e s ample fr equency, r atio is 1 for CGM = 0 and 25/16 for CGM = 1, and all other symbols are shown in Figure 23 on page 22.

By k nowing the M CLK fr equency and d esired s ample rate, the values for the M1, N1, M2, N2 registers can be determined. When determining these values, remember to consider the range for each register as well as the minimum update rate for the first PLL.

The values determined for M1, N1, M2, and N2 must be adjusted by m inus o ne wh en de termining th e va lue written to the respective registers. This is due to internal logic, which adds one to the value stored in the register. This addition allows the user to write a zero value in any of the registers and the effective divide by is one. A special case occurs when both M1 and N1 and/or M2 and N2 are programmed with a zero value. When Mx and Nx ar e bot h zero, the corresponding PLLx is bypassed. Note that if M2 and N2 are set to zero, the ratio of 25/16 is eliminated and cannot be used in the above equation. In this condition the CGM bit has no effect.

Power Management

The S i3035 su pports fou r bas ic po wer man agement operation mo des: nor mal o peration, reset operation, sleep, a nd full p ower d own. T he power management modes ar e controlled b y the PDN and P DL b its o f Register 6.

On power up, or following a reset, the Si3035 is in reset operation. In th is mod e, the PDL bit is set, while the

PDN b it is cleared. T he S i3021 is fully operational, except for the ISOcap link. No communication between the S i3021 and Si3012 c an oc cur du ring reset operation. Any bits associated with the Si3012 are not valid in this mode.

The most c ommon mod e of ope ration is the normal operation. In this mod e, the PDL and PDN b its are cleared. The Si3021 is fully operational and the ISOcap link is passing information between the Si3021 and the Si3012. The clock generator must be programmed to a valid sample rate prior to entering this mode.

The S i3035 s upports a lo w-power s leep mod e. T his mode s upports the popular wak e-up-on-ring feature of many modems. The clock generator registers 7, 8, and 9 must be programmed with valid non-zero values prior to enabling sleep mode. Then, the PDN bit must be set and the P DL bit cleared. When the Si3035 is in sleep mode, th e MC LK s ignal may b e s topped o r r emain active, bu t i t *must* be ac tive be fore waking up th e Si3035. The Si 3021 is non -functional ex cept for the ISOcap and RGDT s ignal. To take the Si3035 out of sleep mode, pulse the reset pin (RESET) low.

In su mmary, the po wer down/up se quence for s leep mode is as follows:

- 1. Registers 7, 8, and 9 must have valid non-zero values.
- 2. Set the PDN bit (Register 6, bit 3) and clear the PDL bit (Register 6, bit 4).
- 3. MCLK may stay active or stop.
- 4. Restore MCLK before initiating the power-up sequence.
- 5. Reset the Si3035 using RESET pin (after MCLK is present).
- 6. Program registers to desired settings.

The Si3035 al so s upports an additional p ower-down mode. When both the PDN (Register 6, bit 3) and PDL (Register 6, bit 4) are set, the chipset enters a complete power-down mode and draws neg ligible c urrent (deep sleep mode). PLL2 should be turned off prior to entering deep sl eep mode (i.e., s et Reg ister 9 to 0 and the n Register 6 to 0x 18). In this mode, the RGDT pin does not function. No rmal operation may be r estored using the s ame process for ta king the chipset out of sl eep mode.

Analog Output

The Si 3035 su pports an ana log output (AOUT) for driving the call p rogress s peaker found with most of today's modems. AO UT is an analog signal that is comprised of a mix of the transmit and receive signals. The receive portion of this mixed signal has a 0 dB gain, while the transmit signal has a gain of -20 dB.

The AOUT level can be adjusted via the ATM and ARM bits in control Register 6. The transmit portion of the



AOUT signal can be set to -20 dB, -26 dB, -32 dB, or mute. The receive portion of the AOUT signal can be set to 0 dB, -6 dB, -12 dB, or mute. Figure 17 on page 17 illustrates a recommended application circuit. In the configuration shown, th e LM 386 p rovides a ga in of 26 dB. Ad ditional gain adjustments may b e m ade by varying the v oltage di vider c reated by R1 and R3 o f Figure 17.

On-Hook Line Monitor

The Si3035 allows the user to detect line activity when the device is in an on-hook state. When the system is on-hook, the line data can be passed to the DSP across the se rial port while dr awing a small am ount of DC current from t he line. This fea ture is similar to the passing of line information (such as c aller ID), while on-hook, following a ring signal detection. To activate this feature, set the ONHM bit in Register 5.

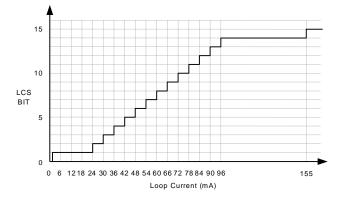
The on-hook line monitor can also be us ed to de tect whether a phone I ine is physically connected to the Si3012 and associated circuitry. When the on-hook line monitor is activated (if no line is connected), the output of SDO will move towards a negative full scale value

(-32768). The value is guaranteed to be at least 89% of negative full scale.

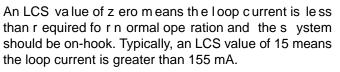
If a line is present while in on-hook line monitor mode, SDO will have a near zero value. The designer must allow for the group de lay of the r eceive filter (12/Fs) before making a decision.

Loop Current Monitor

When the system is in an off-hook state, the LCS bits of Register 12 in dicate the app roximate am ount of DC loop c urrent that is flowing in the loop. The LCS is a 4-bit v alue ranging fr om z ero to fifteen. E ach unit represents approximately 6 mA of lo op current fr om LCS co des 1–14. The typical LCS transfer function is shown in Figure 24.







The LCS detector has a built-in hysteresis of 2 mA of current. This all ows for a stable LCS value when the loop current is near a transition level. The LCS value is a r ough a pproximation of the I oop current, and the designer is advised to use this value in a relative means rather than an absolute value.

This feature enables the host processor to detect if an additional line has "picked up" while the modern is transferring information. In the case of a second phone going off-hook, the loop current falls approximately 50% and is reflected in the value of the LCS bits.

Multiple Device Support

The Si 3035 supp orts the operation of up to seven additional devices on a single serial interface. Figure 25 on page 27 shows the typical connection of the Si3035 and one additional serial voice codec (Si3000).

The Si3035 must be the master in this configuration. The secondary codec should be configured as a slave device with SC LK and F SYNC as in puts. On pow er up, the Si3035 master will be unaware of the additional codec on the ser ial bus. The FC/RGDT pin is an input, operating as the hardware control for secondary frames. The RGDT/FSD pin is an output, operating as the active low ring detection si gnal. It is recommended that the master device be programmed for master/slave m ode prior to enabl ing the ISOc ap, because a ring signal would c ause a false transition to the slave de vice's FSYNC.

Register 14 pr ovides the necessar y control bits to configure the Si30 35 for master/slave oper ation. Bit 0 (DCE) sets the Si 3035 in master/slave m ode, al so referred to as dai sy-chain mode. When the DCE bit is set, the FC/RGDT pin becomes the ring detect output and the RGDT/FSD pin becomes the frame sync del ay output.

Bits 7:5 (NSLV2:NSLV0) set the number of slaves to be supported on the serial bus. For each slave, the Si3035 will generate a FSYNC to the DSP. In daisy-chain mode, the polarity of the ring signal can be controlled by bit 1 (RPOL). When RPOL = 1, the ring detect signal (now output on the FC/RGDT pin) is active high.

The Si3035 supports a variety of codecs (e.g., Si3000) as well as additional Si3035s. The type of slave codec(s) used is set by bits 4:3 (SSEL1:SSEL0). These bits determine the type of signalling used in the LSB of SDO. This assists the D SP in isolating which data stream is the master and which is the slave. If the LSB is used for



signalling, the master device will have a unique setting relative to the slave devices. The <u>D SP c</u> an use this information to determine which FSYNC m arks the beginning of a sequence of data transfers.

The de layed fra me sync (F SD) of e ach devi ce is supplied as the FSYNC of each subseque nt slave device in the d aisy cha in. T he m aster Si3035 will generate an FSYNC signal for each device every 16 or 32 SCLK periods. The delay period is set by Register 14, bit 2 (FSD). Figures 26-29 show the relative timing for daisy chai ning op eration. Pr imary com munication frames occur in sequen ce, followed by secondary communication fr ames, i fre quested. When writing/reading the master device via a secondary frame, all secondar y fra mes of the slave devices must be written as well. When writing/reading a slave device via a secondary frame, the secondary frames of the master and all othe r sl aves must be wr itten as wel I. " No operation" wr ites/reads to s econdary fra mes are accomplished by writing/reading a zero value to address zero.

If FSD is set for 16 SCLK periods between FSYNCs, only serial mode 1 c an be used. In addition, the slave devices must delay the tri-state to active transition of their SDO sufficiently from the rising edge of SCLK to avoid bus contention.

The Si3035 supports the operation of up to eight Si3035 devices on a single serial bus. The master Si3035 must be configured in serial mode 1. The slave(s) Si3035 is configured in serial mode 2. F igure 30 shows a typical master/slave connection using three Si3035 devices.

When i n serial mo de 2, F SYNC becomes an input, RGDT/FSD becomes the delay frame sync output, and FC/RGDT b ecomes the r ing d etection o utput. In addition, the internal PLLs are fixed to a multiply by 20. This provides the desired sample rate when the master's SCLK is provided to the slave's MCLK. The SCLK of the slave is a <u>no</u> connect in this configuration. The delay <u>between</u> FSYNC input and delayed frame sync output (RGDT/FSD) will be 16 SCLK periods. <u>The RGDT/FSD</u> output has a waveform identical to the FSYNC signal in serial mode 0. In addition, the LSB of SDO is set to zero by default for all devices in serial mode 2.

Gain Control

The Si 3035 supports mul tiple gain and attenuation settings for the receive and transmit paths, respectively, via Register 13. When the ARX bit is set, 6 dB of gain is applied to the receive path. When the ATX bit is set, -3 dB of gain is applied to the transmit path.

Register 15 ca n b e us ed to p rovide add itional g ain control. For Register 15 to have an effect on the receive and tr ansmit paths, t he ATX and A RX b its o f

Register 13 must be 0.

The receive path can support gains of 0, 3, 6, 9, and 12 dB. The gain is selected by bits 2:0 (ARX2:ARX0). The receive p ath can al so be muted by setting bit 3 (RXM). The transmit path can support attenuations of 0, 3, 6, 9, and 12 dB. The attenuation is selected by bits 6:4 (ATX2:ATX0). The transmit path can also be muted by setting bit 7 (TXM).

Filter Selection

The Si3035 supports ad ditional filter selections for the receive and transmit signals. When set, the IIRE bit of Register 16 enables the IIR filters defined in Table 12 on page 11. This filter provides a much lower, however non-linear, group delay than the default FIR filters.



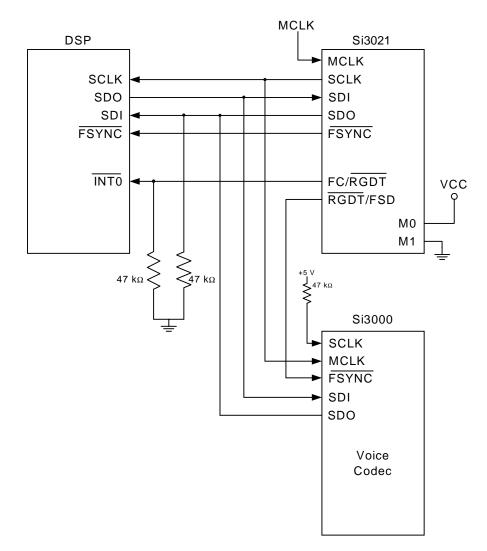


Figure 25. Typical Connection for Master/Slave Operation (e.g., Data/Fax/Voice Modem)



Si3035

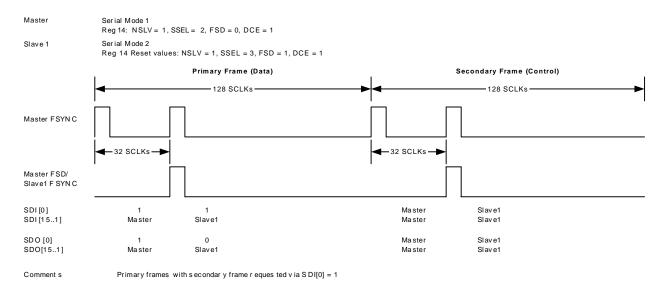


Figure 26. Daisy Chaining of a Single Slave (Pulse FSD)

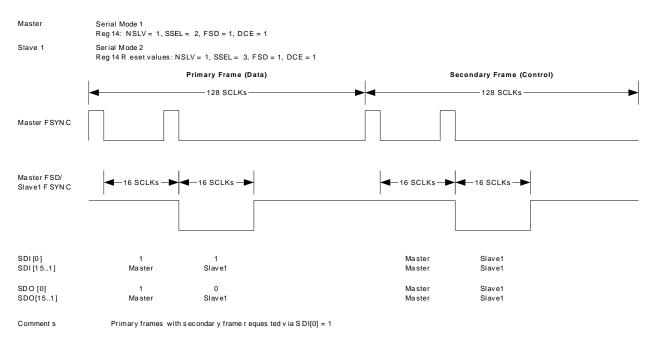


Figure 27. Daisy Chaining of a Single Slave (Frame FSD)



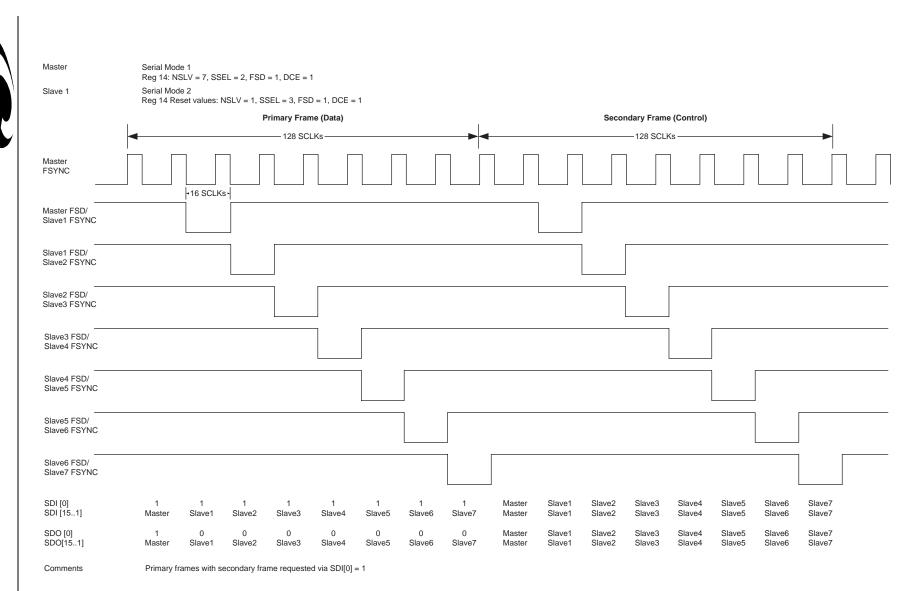


Figure 28. Daisy Chaining of Eight DAAs

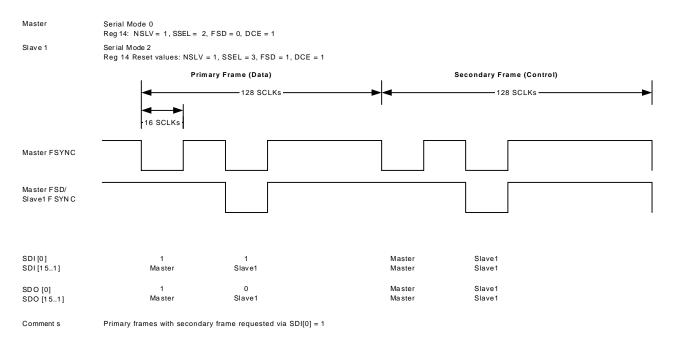


Figure 29. Daisy Chaining with Framed FSYNC and Framed FSD



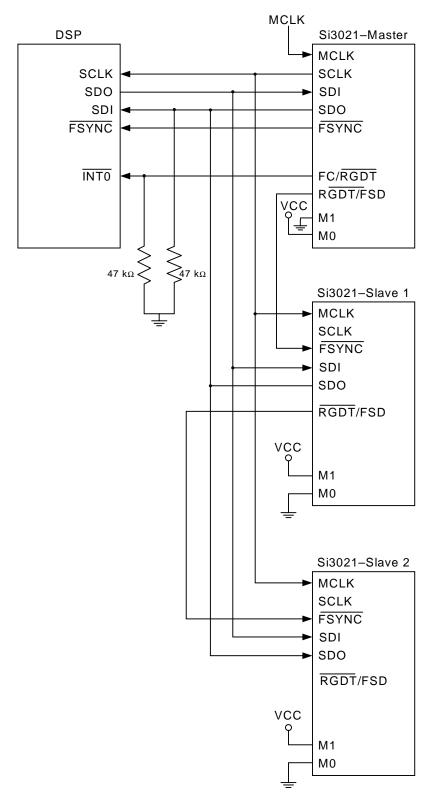


Figure 30. Typical Connection for Multiple Si3035s



Revision Identification

The Si3035 provides the system designer the a bility to determine the revision of the Si3021 and/or the Si3012. Register 11 identifies the revision of the Si3021 with 4 bits named REVA. Register 13 identifies the revision of the Si3012 with 4 bits named RE VB. Table 19 shows the values for the various revisions.

Revision	Si3021	Si3012
А	1000	—
В	1001	—
С	1010	—
D	_	0100
E	_	0101
G	_	0111

Table 19. Revision Values

Calibration

The Si 3035 in itiates an auto-calibration by def ault whenever the device goes off-hook or experiences a loss in line power. Calibration is us ed to remove any offsets that may be present in the on-chip A/D converter which could af fect the A/D dy namic r ange. Auto-calibration is ty pically in itiated after the DA A DC termination s tabilizes and ta kes 512/Fs s econds t o complete. Due to the I arge variation in line conditions and line c ard behavior that may b e pr esented to th e DAA, it can be bene ficial to us e manual calibration in lieu of aut o-calibration. Man ual calibration should be executed as close as possible to 512/Fs seconds before valid transmit/receive data is expected.

The f ollowing steps sh ould b e ta ken to im plement manual calibration:

- 1. The CALD (auto-calibration disable—Register 17) bit must be set to 1.
- 2. The MCAL (manual calibration) bit must be toggled to 1 and then 0 to begin and complete the calibration.
- 3. The calibration will be completed in 512/Fs seconds.

In-Circuit Testing

The Si 3035's advanced des ign pr ovides the modem manufacturer with an increased ability to determine system functionality during production line tests, as well as support for end-user di agnostics. Four loopback modes exist allowing in creased c overage of system components. For three of the test modes, a line-side power source is needed. While a standard phone line

can be used, the test circuit in Figure 1 on page 4 is adequate. In ad dition, an of f-hook s equence must b e performed to connect the power source to the line-side chip.

For the st art-up tes t mod e, no li ne-side power is necessary and no off-hook sequence is required. The start-up test mode is enabled by default. When the PDL bit (Register 6, bit 4) is set (the default case), the line side is in a power-down mode and the DSP-side is in a digital loop-back mode. In this mode, data received on SDI i s passed th rough th e internal f ilters and DO. T his pa th wi ll i ntroduce transmitted on S approximately 0.9 dB of attenuation on the SDI signal received. The group delay of both transmit and receive filters will exist between S DI and SDO. Clearing the PDL bi t di sables t his mo de a nd t he S DO data is switched to the receive data from the line side. When the PDL bit is cleared the FDT bit (Register 12, bit 6) will become ac tive, ind icating the successful communication be tween the li ne-side an d DS P-side. This can be us ed to ve rify that the I SOcap link is operational.

The remaining test modes require an off-hook sequence to operate. The following sequence defines the off-hook requirement:

- 1. Power up or reset.
- 2. Program clock generator to desired sample rate.
- 3. Enable line-side by clearing PDL bit.
- 4. Issue off-hook
- 5. Delay 1548/Fs to allow calibration to occur.
- 6. Set desired test mode.

The ISOcap digital I oopback mod e a llows the dat a pump to provide a digital input test pattern on SDI and receive that digital test pattern back on SDO. To enable this mode, set the DL bit of Register 1. In this mode, the isolation barrier i s ac tually b eing t ested. The d igital stream is delivered across the isolation capacitor, C1 of Figure 16 on pa ge 15, to t he line-side de vice an d returned ac ross the s ame ba rrier. In this mo de, th e 0.9 dB attenuation and filter group delays also exist.

The analog loopback mode allows an external device to drive the RX pin of the line-side chip and receive the signal fr om the T X pin. T his mode allows testing of external c omponents c onnecting th e RJ -11 j ack (TIP and RING) to the line side of the Si3035. To enable this mode, set the AL bit of Register 2.

The final testing mode, internal analog loopback, allows the system to tes t the ba sic operation of the transmit/receive path of the I ine side and the external components R4, R1 8, R2 1, and C5 of F igure 16 o n page 15. In this test mode, the data pump provides a



digital test waveform on SDI. This data is passed across the isolation barrier, looped from the TX to the RX pin, passed back across the isolation barrier, and presented to the dat a pump on SD O. To enable this mode, clear the HBE bit of Register 2.

Clearing the HBE bit will cause a DC of fset which affects the signal swing of the transmit signal. In this test mode, it is recommended that the transmit signal be 12 dB I ower than normal transmit levels. This lower level will eliminate clipping caused by the DC of fset which results from disabling the hybrid. It is assumed in this test that the line AC impedance is nominally 600Ω .

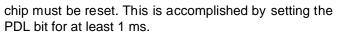
Note: All test modes are mutually exclusive. If more than one test m ode is ena bled co ncurrently, the re sults are unpredictable.

Exception Handling

The Si3035 provides several mechanisms to determine if an er ror occurs dur ing ope ration. Through the secondary frames of the serial link, the controlling DSP can r ead s everal s tatus bi ts. The bit of highest importance i s the f rame de tect bit (FDT, R egister 12, bit 6). This bit indicates that the DSP-side (Si3021) and line-side (Si3012) d evices are communicating. Dur ing normal operation, the FDT bit can be checked before reading any bits that indicate information about the line side. If FDT is not set, the following bits related to th e <u>line-side</u> are invalid: RDT, LCS, CBID, and REVB. The RGDT operation will also be non-functional.

Following po wer-up and r eset, the FDT bit is n ot set because the PDL bit (Register 6, bit 4) defaults to 1. In this s tate, the ISOcap I ink is not operating and n o information about the line-side can be determined. The user m ust program t he clock g enerator t o a valid configuration for the system and c lear the PDL bit to activate the ISOcap link. While the Si3021 and Si3012 are es tablishing communication, the Si3035 will not generate FSYNC s ignals. Establishing communication will tak e less than 10 ms. Therefore, if the controlling DSP s erial interface is interrupt driven, based on the FSYNC signal, the c ontrolling DSP do es not r equire a special delay loop to wait for this event to complete.

The FDT bit can also indicate if the line-side executes an off-hook request successfully. If the line-side is not connected to a phone line (i.e., the user fails to connect a phon e lin e to the mod em), the F DT bit remains cleared. The controlling DSP must allow sufficient time for the line-side to execute the of f-hook request. The maximum time for FDT to be valid following an off-hook request is 10 ms. At this time, the LCS bits indicate the amount of I oop current flowing. For more in formation, see "Loop Current Monitor" on page 25. If the FDT bit fails to be set following an off-hook request, the line-side



Another useful bit is the communication link error (CLE) bit (Register 12, bit 7). The CLE bit indicates a time-out error for the ISO cap link following a c hange to eit her PLL1 o r PL L2. F or m ore i nformation, see " Clock Generation Subsystem" on p age 20. When the CLE bit is se t, the D SP-side ch ip ha s f ailed t o rec eive verification from the line side that the clock change has been accepted in an expected period of time (less than 10 ms). T his c ondition in dicates a s evere er ror i n programming the clock generator or possibly a defective line-side chip.



Control Registers

Any register not listed here is reserved and should not be written.

Table 20. Register Summary

Register	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
1	Control 1	SR						DL	SB
2	Control 2					AL		HBE	RXE
3	Control 3								
4	Control 4								
5	DAA Control 1				OPOL	ONHM	RDT	OHE	OH
6	DAA Control 2	CPE	ATM1	ARM1	PDL	PDN		ATM0	ARM0
7	PLL1 Divide N1				N1[7:0]			
8	PLL1 Multiply M1	M1[7:0]							
9	PLL2 Div./Mult. N2/M2	N2[3:0]					M2[[3:0]	
10	PLL Control								CGM
11	Chip Revision						REVA	A[3:0]	
12	Line Side Status	CLE	FDT				LCS	[3:0]	
13	Transmit and Receive Gain		CBID		REV	B[3:0]		ARX	ATX
14	Daisy-Chain Control	NSLV2	NSLV1	NSLV0	SSEL1	SSEL0	FSD	RPOL	DCE
15	TX/RX Gain Control	ТХМ	ATX2	ATX1	ATX0	RXM	ARX2	ARX1	ARX0
16	IIR Filter Control	000			IIRE	1000			
17	Calibration	0	MCAL	CALD					



Register 1. Control 1

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name	SR						DL	SB
Туре	R/W						R/W	R/W

Reset settings = 0000_0000

Bit	Name	Function
7	SR	Software Reset. 0 = Enables chip for normal operation. 1 = Sets all registers to their reset value.
6:2	Reserved	Read returns zero.
1	DL	 Isolation Digital Loopback. 0 = Disables digital loopback mode across the isolation barrier. 1 = Enables digital loopback mode across the isolation barrier.
0	SB	Serial Digital Interface Mode. 0 = Operation is in 15-bit mode and the LSB of the data field indicates whether a secondary frame is required. 1 = The serial port is operating in 16-bit mode and requires use of the secondary frame sync signal, FC/RGDT, to initiate control data reads/writes.

Register 2. Control 2

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name					AL		HBE	RXE
Туре					R/W		R/W	R/W

Reset settings = 0000_0011

Bit	Name	Function
7:4	Reserved	Read returns zero.
3	AL	Analog Loopback. 0 = Disables analog loopback mode. 1 = Enables analog loopback mode.
2	Reserved	Read returns zero.
1	HBE	Hybrid Enable. 0 = Disconnects hybrid in transmit path. 1 = Connects hybrid in transmit path.
0	RXE	Receive Enable. 0 = Disables receive path. 1 = Enables receive path.



Register 3. Control 3

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name								
Туре								

Reset settings = 0000_0000

Bit	Name	Function
7:0	Reserved	Read returns zero.

Register 4. Control 4

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name								
Туре								

Reset settings = 0000_0000

Bit	Name	Function
7:0	Reserved	Read returns zero.



Register 5. DAA Control 1

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name				OPOL	ONHM	RDT	OHE	OH
Туре				R/W	R/W	R	R/W	R/W

Bit	Name	Function
7:5	Reserved	Read returns zero.
4	OPOL	Off-Hook Polarity. 0 = Off-hook pin is active low. 1 = Off-hook pin is active high.
3	ONHM	 On-Hook Line Monitor. 0 = Normal on-hook mode. 1 = Enables low-power monitoring mode allowing the DSP to receive line activity without going off-hook. This mode is used for caller ID detection.
2	RDT	Ring Detect . 0 = No ring is occurring. Reset either 4.5–9 seconds after last positive ring is detected or when the system executes an off-hook. 1 = Indicates a ring is occurring.
1	OHE	Off-Hook Pin Enable. 0 = Off-hook pin is ignored. 1 = Enables the operation of the off-hook pin.
0	ОН	Off-Hook. 0 = Line side chip is on-hook. 1 = Causes the line side chip to go off-hook. This bit operates independently of OHE and is a logic OR with the off-hook pin when OHE = 1.



Register 6. DAA Control 2

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name	CPE	ATM1	ARM1	PDL P	DN		ATM0	ARM0
Туре	R/W	R/W	R/W	R/W	R/W		R/W	R/W

Reset settings = 0111_0000

Bit	Name	Function
7	CPE	Charge Pump Enable. 0 = Charge pump is disabled. 1 = Charge pump is enabled. (The VA pin should not be connected to a supply. VD = 3.3 V ± 10%.)
6,1	ATM[1:0]	 AOUT Transmit Path Level Control. 00 = -20 dB transmit path attenuation for call progress AOUT pin only. 01 = -32 dB transmit path attenuation for call progress AOUT pin only. 10 = Mutes transmit path for call progress AOUT pin only. 11 = -26 dB transmit path attenuation for call progress AOUT pin only.
5,0	ARM[1:0]	 AOUT Receive Path Level Control. 00 = 0 dB receive path attenuation for call progress AOUT pin only. 01 = -12 dB receive path attenuation for call progress AOUT pin only. 10 = Mutes receive path for call progress AOUT pin only. 11 = -6 dB receive path attenuation for call progress AOUT pin only.
4	PDL	 Power Down Line-Side Chip. 0 = Normal operation. Program the clock generator before clearing this bit. 1 = Places the Si3012 in power down or reset state.
3	PDN	Power Down. 0 = Normal operation. 1 = Powers down the Si3021. A pulse on RESET is required to restore normal operation.
2	Reserved	Read returns zero.

Register 7. PLL1 Divide N1

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name		N1[7:0]						
Туре				R/	W			

Reset settings = 0000_0000 (serial mode 0, 1, 2)

Bit	Name	Function
7:0	N1[7:0]	N1 Divider.
		Contains the (value – 1) for determining the output frequency on PLL1.



Register 8. PLL1 Multiply M1

Bit	D7	D6	D5	D4	D3	D2	D1	D0				
Name		M1[7:0]										
Туре				R/	W		R/W					

Reset settings = 0000_0000 (serial mode 0, 1)

Reset settings = 0001_0011 (serial mode 2)

Bit	Name	Function
7:0	M1[7:0]	M1 Multiplier.
		Contains the (value – 1) for determining the output frequency on PLL1

Register 9. PLL2 Divide/Multiply N2/M2

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name		N2[3:0]		M2[3:0]			
Туре		R/	W			R/	W	

Reset settings = 0000_0000 (serial mode 0, 1, 2)

Bit	Name	Function
7:4	N2[3:0]	N2 Divider. Contains the (value – 1) for determining the output frequency on PLL2.
3:0	M2[3:0]	M2 Multiplier. Contains the (value – 1) for determining the output frequency on PLL2.

Register 10. PLL Control Register

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name								CGM
Туре								R/W

Bit	Name	Function
7:1	Reserved	Read returns zero.
0	CGM	 Clock Generation Mode. 0 = No additional ratio is applied to the PLL and faster lock times are possible. 1 = A 25/16 ratio is applied to the PLL allowing for a more flexible choice of MCLK frequencies while slowing down the PLL lock time.



Register 11. Chip Revision

Bit	D7	D6	D5	D4	D3	D2	D1	D0	
Name					REVA				
Туре					-	R[3	3:0]		

Reset settings = N/A

Bit	Name	Function
7:4	Reserved	Read returns zero.
3:0	REVA[3:0]	Chip Revision. Four-bit value indicating the revision of the Si3021 (DSP-side) chip.

Register 12. Line Side Status

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name	CLE	FDT				LCS	[3:0]	•
Туре	R/W	R				F	२	

Reset settings = N/A

Bit	Name	Function
7	CLE	Communications (ISOcap Link) Error . 0 = ISOcap communication link between the Si3021 and the Si3012 is operating correctly. 1 = Indicates a communication problem between the Si3021 and the Si3012. A write of 0 or a reset is required to clear this bit.
6F	DT	Frame Detect. 0 = Indicates ISOcap link has not established frame lock. 1 = Indicates ISOcap link frame lock has been established.
5:4	Reserved	Read returns zero.
3:0	LCS[3:0]	Loop Current Sense. Four-bit value returning the loop current in 6 mA increments. 0 = Loop current < 0.4 mA typical. 1111= Loop current > 155 mA typical. See "Loop Current Monitor" on page 25.



Register 13. Transmit and Receive Gain

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name		CBID		REVE	3[3:0]		ARX	ATX
Туре		R		R				R/W

Bit	Name	Function
7	Reserved	Read returns zero.
6	CBID	Chip B ID.
		0 = Indicates the line side is domestic only.
		1 = Indicates the line side has international support.
5:2	REVB[3:0]	Chip Revision.
		Four-bit value indicating the revision of the Si3012 (line-side) chip.
1	ARX	Receive Gain.
		0 = 0 dB gain is applied to the receive path.
		1 = 6 dB gain is applied to the receive path.
		Note: This bit should be zero if using Register 15 to control gain.
0	ATX	Transmit Gain.
		0 = 0 dB gain is applied to the receive path.
		1 = -3 dB gain (attenuation) is applied to the transmit path.
		Note: This bit should be 0 if using Register 15 to control gain.



Register 14. Daisy-Chain Control

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name	NSLV2	NSLV1	NSLV0	SSEL1	SSEL0	FSD	RPOL	DCE
Туре	R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W

Reset settings = 0000_0010 (serial mode 0, 1) Reset settings = 0011_1111 (serial mode 2)

Bit	Name	Function
7:5	NSLV[2:0]	Number of Slave Devices. 000 = 0 slaves. Simply redefines the FC/RGDT and RGDT/FSD pins. 001 = 1 slave device. 010 = 2 slave devices. 011 = 3 slave devices. 100 = 4 slave devices. (For four or more slave devices, the FSD bit MUST be set.) 101 = 5 slave devices. 110 = 6 slave devices. 111 = 7 slave devices.
4:3	SSEL[1:0]	Slave Device Select. 00 = 16-bit SDO receive data. 01 = Reserved. 10 = 15-bit SDO receive data. LSB = 1 for the Si3035 device. 11 = 15-bit SDO receive data. LSB = 0 for the Si3035 device.
2F	SD	Delayed Frame Sync Control. 0 = Sets the number of SCLK periods between frame syncs to 32. 1 = Sets the number of SCLK periods between frame syncs to 16. This bit MUST be set when Si3035 devices are slaves. For the master Si3035, only serial mode 1 is allowed in this case.
1R	POL	Ring Detect Polarity.0 = The FC/RGDT pin (operating as ring detect) is active low.1 = The FC/RGDT pin (operating as ring detect) is active high.
0	DCE	Daisy-Chain Enable. 0 = Daisy chaining disabled. 1 = Enables the Si3035 to operate with slave devices on the same serial bus. The FC/RGDT signal (pin 7) becomes the ring detect output and the RDGT/FSD signal (pin 15) becomes the delayed frame sync signal. Note that ALL other bits in this register are ignored if DCE = 0.



Register 15.TX/RX Gain Control

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name	ТХМ	ATX2	ATX1	ATX0	RXM	ARX2	ARX1	ARX0
Туре	R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W

Bit	Name	Function
7	ТХМ	Transmit Mute. 0 = Transmit signal is not muted. 1 = Mutes the transmit signal.
6:4	ATX[2:0]	Analog Transmit Attenuation. 000 = 0 dB attenuation. 001 = 3 dB attenuation. 010 = 6 dB attenuation. 011 = 9 dB attenuation. 1xx = 12 dB attenuation. Note: Register 13 ATX bit must be 0 if these bits are used.
3	RXM	Receive Mute. 0 = Receive signal is not muted. 1 = Mutes the receive signal.
2:0	ARX[2:0]	Analog Receive Gain. 000 = 0 dB gain. 001 = 3 dB gain. 010 = 6 dB gain. 011 = 9 dB gain 1xx = 12 dB gain. Note: Register 13 ARX bit must be 0 if these bits are used.



Register 16. IIR Filter Control

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name	0	0	0	IIRE	1	0	0	0
Туре	R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W

Reset settings = 0000_1000

Bit	Name	Function
7:5	Reserved	Read returns zero (must always be written with zeroes).
4	IIRE	 IIR Filter Enable. 0 = FIR filter enabled. 1 = Transmit and receive filters are realized with an IIR filter characteristic. To enable IIR filter write 0x18; to disable IIR filter write 0x08. See Table 12 on page 11 for more details on IIR filter performance.
3:0	Reserved	Read returns 0x8 (must always be written with 0x8).

Register 17. International Control

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name	0	MCAL	CALD					
Туре		R/W	R/W					

Bit	Name	Function
7	Reserved	Must be zero.
6	MCAL	Manual Calibration. 0 = No calibration. 1 = Initiate calibration.
5	CALD	Auto-Calibration.0 = Auto-calibration enabled.1 = Auto-calibration disabled.
4:0	Reserved	Read returns zero.



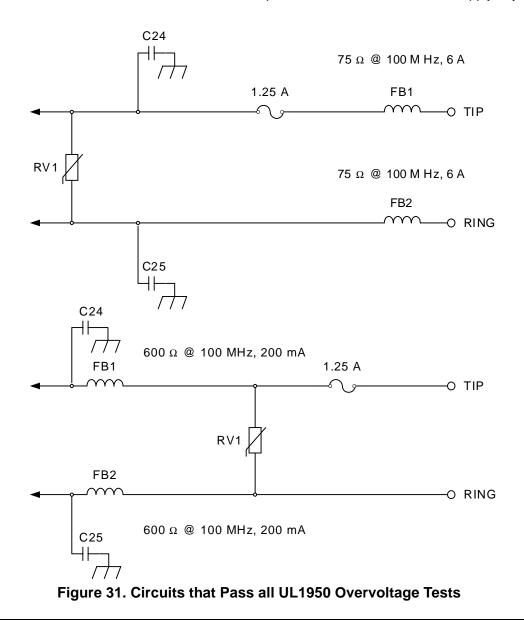
APPENDIX-UL1950 3RD EDITION

Although designs using the Si3035 comply with UL1950 3rd Ed ition and pass all ov ercurrent and overvoltage tests, there are still several issues to consider.

Figure 31 shows two designs that can pass the UL1950 overvoltage tests, as well as electromagnetic emissions. The top schematic of Figure 31 shows the configuration in which the ferrite beads (FB1, FB2) are on the unprotected side of the sidactor (RV1). For this configuration, the current rating of the ferrite beads needs to be 6 A. Howe ver, the h igher current ferrite beads are less effective in reducing electromagnetic emissions.

The b ottom sc hematic of F igure 31 s hows th e configuration in which the ferrite beads (FB1, FB2) are on the protected s ide of the s idactor (RV1). For this design, the ferrite beads can be rated at 200 mA.

In a cost optimized design, it is important to remember that c ompliance t o UL 1950 do es no t al ways require overvoltage t ests. It i s b est to p lan ahe ad and know which ov ervoltage t ests will apply t o yo ur system. System-level elements in the construction, such as fire enclosure and s pacing r equirements, need to be considered during the design stages. Consult with your professional tes ting ag ency during the des ign of th e product to determine which tests apply to your system.





Pin Descriptions: Si3021

Si3021 (SOIC)			S	Si3021 (TSSOP)		
	1• 16		SDO	1• 16	□ v _D	
FSYNC	2 15	RGDT/FSD	SDI	2 15	SCLK	
SCLK	3 14	M0	FC/RGDT	3 14	FSYNC	
VD	4 13	V _A	RESET	4 13	MCLK	
SDO 🗌	5 12	GND	AOUT	5 12		
SDI 🗌	6 11	C1A	M1	6 11	RGDT/FSD	
FC/RGDT	7 10	M1	C1A	7 10	MO	
RESET	8 9		GND	8 9	□ V _A	

Table 21. Si3021 Pin Descriptions

SOIC Pin #	TSSOP Pin #	Pin Name	Description
1	13	MCLK	Master Clock Input. High speed m aster c lock i nput. Generally s upplied by t he system crystal clock or modem/DSP.
2	14	FSYNC	Frame Sync Output. Data fr aming si gnal t hat i s u sed to ind icate the s tart a nd s top of a communication/data frame.
3	15	SCLK	Serial Port Bit Clock Output. Controls the serial data on SDO and latches the data on SDI.
41	6	V _D	Digital Supply Voltage. Provides the digital supply voltage to the Si3021, nominally either 5 V or 3.3 V.
51		SDO	Serial Port Data Output. Serial communication data that is provided by the Si3021 to the modem/DSP.
62		SDI	Serial Port Data Input. Serial communication and control data that is generated by the modem/DSP and presented as an input to the Si3021.
7	3	FC/RGDT	Secondary Transfer Request Input/Ring Detect Output. An optional signal to instruct the Si3021 that control data is being requested in a secondary frame. When daisy chain is enabled, this pin becomes the ring detect output. Produces an active low rectified version of the ring signal.
8	4	RESET	Reset Input. An active low input that is used to reset all control registers to a defined, ini- tialized state. Also used to bring the Si3034 out of sleep mode.
9	5	AOUT	Analog Speaker Output. Provides an analog output signal for driving a call progress speaker.



SOIC Pin #	TSSOP Pin #	Pin Name	Description
10	6	M1	Mode Select 1 Input. The second of two mode select pins that is used to select the operation of the serial port/DSP interface.
11	7	C1A	Isolation Capacitor 1A. Connects to one side of the isolation capacitor C1. Used to communicated with the line-side device.
12	8	GND	Ground. Connects to the system digital ground.
13	9	V _A	Analog Supply Voltage. Provides the analog supply voltage for the Si3021, nominally 5 V. This supply is typically generated internally with an on-chip charge pump set through a control register.
14	10	MO	Mode Select 0 Input. The first of two mode select pins that is used to select the operation of the serial port/DSP interface.
15	11	RGDT/FSD	Ring Detect/Delayed Frame Sync Output. Output signal that indicates the status of a ring signal. Produces an active low rectified version of the ring signal. When daisy chain is enabled, this sig- nal becomes a delayed frame sync to drive a slave device.
16	12	OFHK	Off-Hook Input. An active low input control signal that provides a termination across TIP and RING for line seizing and pulse dialing.

Table 21. Si3021 Pin Descriptions (Continued)



Pin Descriptions: Si3012

Si3012 (SOIC or TSSOP)

TSTA	1.		
_	1 -		
TSTB	2	15 🗌 NC	
IGND	3	14 🗌 RX	
C1B	4	13 🗌 REXT	
RNG1	5	12 🗌 DCT	
RNG2	6	11 HYBD	
QB	7	10 VREG2	
QE	8	9 VREG	

Table 22. Si3012 Pin Descriptions

(SOIC or TSSOP) Pin #	Pin Name	Description
1T	STA	Test Input A. Allows a ccess to test modes which a re reserved for factory use. This p in has a n internal pull-up and should be left as a no connect for normal operation.
2T	STB	Test Input B. Allows a ccess to test modes which a re reserved for factory use. This p in has a n internal pull-up and should be left as a no connect for normal operation.
31	GND	Isolated Ground. Connects to ground on the line-side interface.
4C	1B	Isolation Capacitor 1B. Connects to one side of isolation capacitor C1.
5R	NG1	Ring 1 Input. Connects through a capacitor to the TIP lead of the telephone line. Provides the ring and caller ID signals to the Si3035.
6R	NG2	Ring 2 Input. Connects through a capacitor to the RING lead of the telephone line. Provides the ring and caller ID signals to the Si3035.
7Q	В	Transistor Base. Connects to the base of the hookswitch transistor, Q3.
8Q	E	Transistor Emitter. Connects to the emitter of the hookswitch transistor, Q3.
9V	REG	Voltage Regulator. Connects to an external capacitor to provide bypassing for an internal voltage regulator.
10	VREG2	Voltage Regulator 2. Connects to an external capacitor to provide bypassing for an internal voltage regulator.



(SOIC or TSSOP) Pin #	Pin Name	Description
11	HYBD	Hybrid Node Output. Balancing capacitor connection used for JATE out-of-band noise support.
12	DCT	DC Termination. Provides DC termination to the telephone network.
13	REXT	External Resistor. Connects to an external resistor.
14	RX	Receive Input. Serves as the receive-side input from the telephone network.
15	NC	No Connect.
16	ТХ	Transmit Output. Provides the output through an AC termination impedance to the telephone network.

Table 22. Si3012 Pin Descriptions (Continued)



Ordering Guide

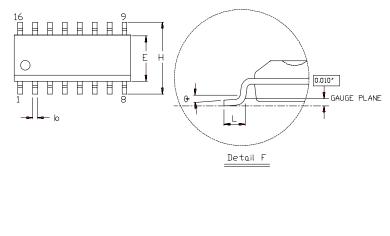
Chipset	Region	Interface	Digital (SOIC)	Line (SOIC)	Digital (TSSOP)	Line (TSSOP)	Temperature
Si3034	Global	DSP Serial I/F	Si3021-KS	Si3014-KS	Si3021-KT	Si3014-KT	0°C to 70°C
Si3035	FCC/Japan	DSP Serial I/F	Si3021-KS	Si3012-KS	Si3021-KT	Si3012-KT	0°C to 70°C
Si3036	FCC/Japan	AC Link	Si3024-KS	Si3012-KS	Si3024-KT	Si3012-KT	0°C to 70°C
Si3038	Global	AC Link	Si3024-KS	Si3014-KS	Si3024-KT	Si3014-KT	0°C to 70°C
Si3044	Enhanced Global	DSP Serial I/F	Si3021-KS	Si3015-KS			0°C to 70°C
Si3044	Enhanced Global	DSP Serial I/F	Si3021-BS	Si3015-BS			–40°C to 85°C
Si3046	FCC/JATE	AC Link	Si3025-KS	Si3012-KS			0°C to 70°C
Si3048	Global	AC Link	Si3025-KS	Si3014-KS			0°C to 70°C

Table 23. Ordering Guide



SOIC Outline

Figure 32 illustrates the package details for the Si3021 and Si3012. Table 24 lists the values for the dimensions shown in the illustration.



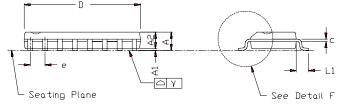


Figure 32. 16-pin Small Outline Plastic Package (SOIC)

Controlling	Dimension:	mm
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Symbol	Incl	nes	Millime	eters
	Min	Max	Min	Max
A	0.053	0.069	1.35	1.75
A1	0.004	0.010	0.10	0.25
A2	0.051	0.059	1.30	1.50
b	0.013	0.020	0.330	0.51
С	0.007	0.010	0.19	0.25
D	0.386	0.394	9.80	10.01
E	0.150	0.157	3.80	4.00
е	0.050 BSC	_	1.27 BSC	_
Н	0.228	0.244	5.80	6.20
L	0.016	0.050	0.40	1.27
L1	0.042 BSC	_	1.07 BSC	_
γ	—	0.004	—	0.10
θ	0°	8°	0°	8°



TSSOP Outline

Figure 33 illustrates the package details for the Si3021 and Si3014. Table 25 lists the values for the dimensions shown in the illustration.

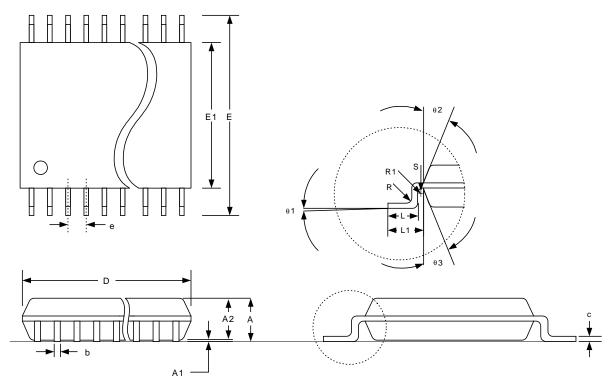


Figure 33. 16-pin Thin Small Shrink Outline Package (TSSOP)

Symbol	Millimeters			
	Min	Nom	Max	1
А	_	1.10	1.20	
A1	0.05	_	0.15	
A2	0.80	1.00	1.05	
b	0.19		0.30	
С	0.09		0.20	
D	4.85	5.00	5.15	
е	0.65 SC			В
E	6.40 SC			В
E1	4.30	4.40	4.50	
L	0.45	0.60	0.75	
L1	1.00 REF			
R	0.09	_	—	
R1	0.09		—	
S	0.20	_	—	
θ1	0	—	8	
θ2	12 REF			
θ3	12 REF			

Table 25. Package Diagram Dimensions



Data Sheet Changes from Version 1.0 to Version 1.1

- Typical Application Circuit was updated.
- C24, C25 value changed from 470 pF to 1000 pF and C31, C32 were added in Table 13. The tolerance was also changed from 20% to 10%.
- Power Supply Voltage, Analog maximum changed from 4.75 V to 5.00 V in Table 4.
- Last paragraph updated in "Power Management" text section.

Data Sheet Changes from Version 1.1 to Version 1.2

- TSSOP information added.
- Total supply currents updated in Table 3 and Table 4.
- Cycle time updated in Table 7.
- Delay times updated in Table 8, Table 9, and Table 10.
- Figure 4 updated.
- Revision G values added in Table 19.
- Figure 16, "Typical Application Schematic," on page 15 updated.
- Table 13, "Component Values—Typical Application," on page 16 (BOM) updated.



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